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## **Aec Q100 Rev H Aecmain**

Revision Summary This informative section briefly describes the changes made in the AEC-Q100 Rev-H document, compared to previous document version, AEC-Q100 Rev-G (May 14, 2007).

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Punctuation and text improvements are not included in this summary.

## **FAILURE MECHANISM BASED STRESS TEST ... - AECMain**

of ELFR B2 AEC-Q100-008 Early Life  
Failure Rate: (Test @ Rm/Hot) of EDR B3  
AEC-Q100-005 NVM Endurance & Data  
Retention Test: (Test @ Rm/Hot) of TEST

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GROUP C - PACKAGE ASSEMBLY  
INTEGRITY TESTS WBS C1 AEC-  
Q100-001. AEC-Q003 Wire Bond Shear  
Test: (Cpk > 1.67) 30 bonds 5 parts.  
Min. bonds of WBP C2 Mil-STD-883,  
Method 2011

**Supplier Name: - AECMain**

AEC - Q100 Rev - H: Failure Mechanism

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Based Stress Test Qualification For  
Integrated Circuits (base document) AEC  
- Q100-001 - Rev-C : Wire Bond Shear  
Test AEC - Q100-002 - Rev-E : Human  
Body Model (HBM) Electrostatic  
Discharge Test

## **AEC Documents - AECMain**

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AEC - Q100-002 - Rev-E: Human Body Model (HBM) Electrostatic Discharge Test  
AEC - Q100-004 - Rev-D: IC Latch-Up Test  
AEC - Q100-005 - Rev-D1: Non-Volatile Memory Program/Erase Endurance, Data Retention, and Operational Life Test  
AEC - Q100-012 - Rev-: Short Circuit Reliability Characterization of Smart Power Devices

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for 12V Systems

## **Fundamentals of AEC-Q100: What “Automotive Qualified ...**

Successful completion and documentation of the test results from requirements outlined in this document allows the supplier to claim that the part is “AEC Q100 qualified”. The supplier, in

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agreement with the user, can perform qualification at sample sizes and conditions less stringent than what this document requires.

## **STRESS TEST QUALIFICATION FOR INTEGRATED CIRCUITS - AECMain**

AEC - Q100 - REV-G May 14, 2007

Component Technical Committee

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Automotive Electronics Council Page 3 of 32 2.1.1 Zero Defects Qualification and some other aspects of this document are a subset of, and contribute to, the

## **FAILURE MECHANISM BASED STRESS TEST ... - AECMain**

AEC Documents - AECMain. Live  
aecouncil.com. AEC - Q100 Rev H - CDC

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Template: Certificate of Design,  
Construction and Qualification (as  
published in AEC - Q100 Rev - H) AEC -  
Q100 Rev H - QTP Template:  
Qualification Test Plan (as published in  
AEC - Q100 Rev - H) AEC - Q104 Initial  
Release - CDC Template: Certificate of  
Design, Construction and ...



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## **Aec Dep Certificate - 12/2020**

Beyond AEC-Q100 certification, National's manufacturing process distinguishes its Automotive-Grade products from others with: Special manufacturing flow with increased inspection and screening Enhanced defect detection through methods including PAT, delta current stress tests,

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statistical bin yield analysis, and  
reliability monitors

## **Automotive Grade Quality Products (AEC-Q100 and ...**

As part of this qualification, the AEC-Q100-REV G Automotive Qualification the IXD\_609SI product family was subjected to Human Body Model (HBM)

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ESD Sensitivity Classification testing using a KeyTek Zapmaster system.

## **AEC-Q100 Automotive Qualification IXDD609SI.IXDI609SI ...**

AEC-Q100 is a failure mechanism based stress test qualification for packaged integrated circuits. The Automotive Electronics Council (AEC) is based in the

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United States and was originally established by three major automotive manufacturers for the purpose of establishing common part-qualification and quality-system standards.

## **AEC-Q100 | Renesas**

AEC-Q100-REV H-QTP Document No.  
002-29234 Rev: \*\* Page 1 of 6 Company

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Confidential Cypress Semiconductor  
Automotive Reliability Qualification  
Report AEC-Q100 Automotive  
Qualification Test Plan Report for  
Qualification of Greatek As Alternate  
Assembly Location for SOIC008, Grade 3  
-40 to 85C ...

**PRODUCT CHANGE NOTIFICATION -**

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## **Future Electronics**

AEC-Q100-010 Solder Ball Shear (SBS):  
Performed on all solder ball mounted packages e.g. PBGA, Chip Scale, Micro Lead Frame (but NOT Flip Chip). Two reflow cycles at MSL reflow temperature before shear. Cpk = or  $>1.67$  10 (5 balls from a min. of 10 devices) 0 0 For solder ball mounted packages only; NOT for

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Flip Chips.

## **AEC-Q100G Qualification Report - NXP Semiconductors**

AEC-Q100 establishes common part-qualification and quality-system standards for automotive electronics, and is the industry-standard specification that outlines the

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recommended new product and major change qualification requirements and procedures for packaged integrated circuits embedded into automotive applications.

**Meaning of AEC-Q100 - KBA220733 |  
Cypress Developer Community**  
ADI\_PCN\_10\_0006\_Rev\_H\_Mini SOIC



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Qualification Data.doc Attachment 2:  
Type: Qualification Report Summary  
ADI\_PCN\_10\_0006\_Rev\_H\_Mini SOIC AEC-  
Q100 Qualification Data Rev C.doc For  
questions on this PCN, send email to the  
regional contacts below or contact your  
local ADI sales representative

## **Product/Process Change Notice -**

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## **PCN 10 0006 Rev. H**

The Automotive Electronics Council (AEC) provides the AEC Q100-012 documentation which specifies standards for short-circuit reliability testing. The main purpose of this test is to determine the reliability of smart-power switches when operating in a continuous short-circuit condition.

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## **AEC-Q100-012 Short-Circuit Reliability Test Results for ...**

Document Number: 002-14857 Rev. \*H  
Revised April 25, 2017 The Cypress  
CYW89071 is a monolithic, single-chip,  
Bluetooth 4.1 compliant, stand-alone  
baseband processor with an integrated  
2.4 GHz transceiver. Manufactured using

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the industry's most advanced 65 nm CMOS low-power process, the CYW89071 employs

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